Future wireless systems such as door controls, light controls, home entertainment, and environment-control systems will be controlled and used through wireless interfaces such as the emerging 3G systems. Because such interfaces contain digital, analog, mixed and RF components together with considerable embedded software, adequate testing will become extremely difficult. A major question is how will the handheld terminals, wireless applications and base stations be tested to ensure interoperability (IOP), reliability and the quality of services? And when it doesn’t work properly, how easy will it be to locate the fault – to the handheld device, to the application system, to the terminal/base station connection, or to an associated landline?

The main objective of this panel is to discuss the possible ways of testing very complex 3G-controlled systems and products to ensure IOP, reliability and quality of services. The other issues will be life cycle testing strategies, methods and co-operation needs for wireless test standardization to reduce total cost of testing the wireless system and products.

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